Application/Control No.	Applicant(s)/Patent under Reexamination
10/658,833	CHOU, CHUNG-CHENG
Examiner	Art Unit
Vu A. Le	2824



		IS	SUE CLASSIFICA	TION									
0	RIGINAL		CROSS REFERENCE(S)										
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)										
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INTERNATION	AL CLASSIFICATION												
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	24/16	Date)	Vu A. Le (Primary Examiner)	O.G. O'G. Print Claim(s) Print FI 1 8									

\boxtimes	Claims renumbered in the same order as presented by applicant									☐ CPA			☐ T.D.			☐ R.1.47			
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
	1			31			61			91			121			151			181
	2			32			62			92			122			152			182
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	6			36			66			96			126			156			186
	7			37			67			97			127			157			187
	8			38			68			98			128			158			188
	9			39			69			99			129			159			189
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	11			41			71			101			131			161			191
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